

AO4948-VB Datasheet

Dual N-Channel Enhancement Mode Field Effect Transistor with Schottky Diode

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A)	Q _g (Typ.)			
30	$0.008 \text{ at V}_{GS} = 10 \text{ V}$	8	15 nC			
	0.012 at V _{GS} = 4.5 V	6.8	15110			

□ D2/K 7 **b** D2/K

6 🗖 D1

5 🗖 D1

SOIC-8

S2/A □

G2**□**

S1 🗖

FEATURES

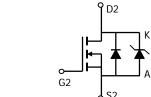
- Halogen-free According to IEC 61249-2-21 Definition
- TrenchFET® Power MOSFET
- 100 % UIS Tested
- 100 % R_g Tested Compliant to RoHS Directive 2002/95/EC

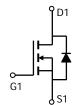


HALOGEN FREE

APPLICATIONS

- Set Top Box
- Low Current DC/DC





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Absolute Maximum Ratings T _A =25°C unless otherwise noted						
Parameter	Symbol V _{DS}	MOSFET 30	Schottky	Units V		
Drain-Source Voltage						
Gate-Source Voltage		V_{GS}	±12		V	
	T _A =25°C	_	8			
Continuous Drain Current ^A	T _A =70°C	- I _D	6.8		Α	
Pulsed Drain Current ^B	I _{DM}	40				
Schottky reverse voltage		V_{KA}		30	V	
	T _A =25°C	- I _F		3		
Continuous Forward Current ^A	T _A =70°C] 'F		2	Α	
Pulsed Forward Current ^B		I _{FM}		40		
	T _A =25°C	P _D	2	2	W	
Power Dissipation	T _A =70°C	r _D	1.44	1.44] vv	
Junction and Storage Temperature Range		T_J, T_{STG}	-55 to 150	-55 to 150	°C	

Parameter: Thermal Characteris	Symbol	Тур	Max	Units		
Maximum Junction-to-Ambient ^A	t ≤ 10s	$R_{\theta JA}$	48	62.5		
Maximum Junction-to-Ambient ^A	Steady-State		74	110	°C/W	
Maximum Junction-to-Lead ^C	Steady-State R _{eJL}		35	40		
Thermal Characteristics Schottky						
Maximum Junction-to-Ambient ^A t ≤ 10s		$R_{\theta JA}$	47.5	62.5		
Maximum Junction-to-Ambient ^A	Steady-State	·γθJA	71	110	°C/W	
Maximum Junction-to-Lead ^C	Steady-State	$R_{ heta JL}$	32	40		

服务热线:400-655-8788

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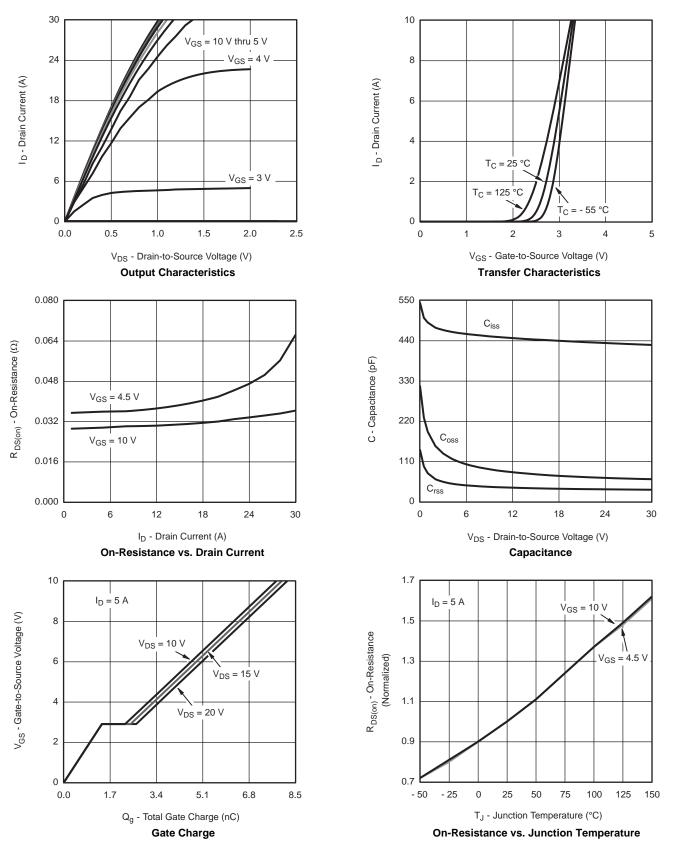
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static			•		l	•	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		32			
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 5.0		mV/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	1.0		2.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
	I _{DSS}	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$			1		
Zero Gate Voltage Drain Current		V _{DS} = 30 V, V _{GS} = 0 V, T _J = 55 °C			10	μA	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	10			Α	
		V _{GS} = 10 V, I _D = 5 A		0.008		Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 4 \text{ A}$		0.012			
Forward Transconductance ^a	g _{fs}	V _{DS} = 10 V, I _D = 5 A		16		S	
Dynamic ^b	<u> </u>		I		<u> </u>	1	
Input Capacitance	C _{iss}			586			
Output Capacitance	C _{oss}	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		117		pF	
Reverse Transfer Capacitance	C _{rss}			55			
Total Gate Charge		$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 5 \text{ A}$		15			
	Qg			3.7	5.6		
Gate-Source Charge	Q _{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 5 \text{ A}$		1.4		nC	
Gate-Drain Charge	Q _{gd}			1.05			
Gate Resistance	R _g	f = 1 MHz	0.8	4.3	8.6	Ω	
Turn-On Delay Time	t _{d(on)}			12	24		
Rise Time	t _r	V_{DD} = 15 V, R_L = 3 Ω		55	100		
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 5$ A, V_{GEN} = 4.5 V, R_g = 1 Ω		11	22	1	
Fall Time	t _f			8	16	1	
Turn-On Delay Time	t _{d(on)}			4	8	ns	
Rise Time	t _r	V_{DD} = 15 V, R_L = 3 Ω		9	18	-	
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 5$ A, V_{GEN} = 10 V, R_g = 1 Ω		10	20		
Fall Time	t _f			6	12	1	
Drain-Source Body Diode Characteristi	cs				<u> </u>		
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			2.25	٨	
Pulse Diode Forward Current	I _{SM}				24	A	
Body Diode Voltage	V_{SD}	I _S = 2 A, V _{GS} = 0 V		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			11	20	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = 5 A, dI/dt = 100 A/μs, T _J = 25 °C		4	8	nC	
Reverse Recovery Fall Time	t _a	$I_F = 3 \text{ A}$, $I_J = 25 \text{ C}$		7			
Reverse Recovery Rise Time	se Time t _b			4		ns	

Notes:

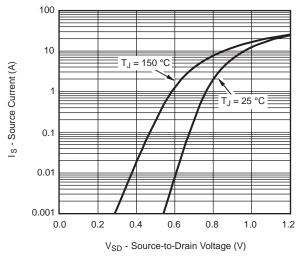
- a. Pulse test; pulse width $\leq 300~\mu s,~duty~cycle \leq 2~\%$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

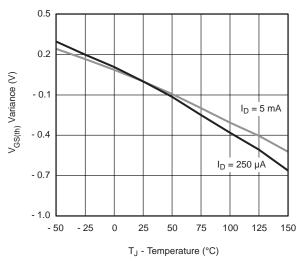




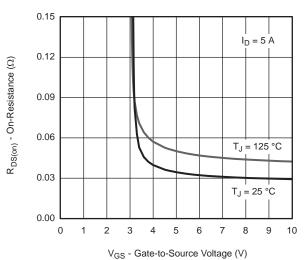




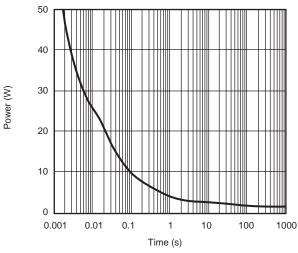
Source-Drain Diode Forward Voltage



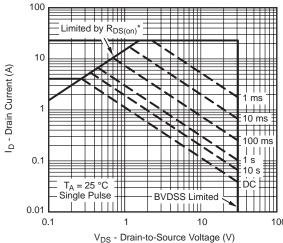
Threshold Voltage



On-Resistance vs. Gate-to-Source Voltage



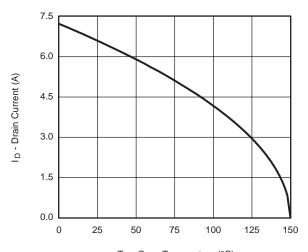
Single Pulse Power



* V_{GS} > minimum V_{GS} at which R_{DS(on)} is specified

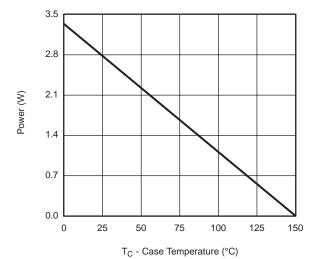
Safe Operating Area, Junction-to-Ambient



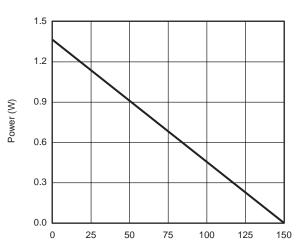


T_C - Case Temperature (°C)

Current Derating*



Power, Junction-to-Foot

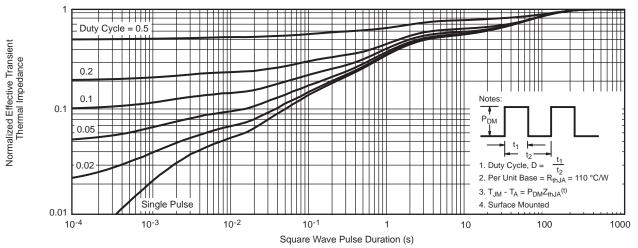


T_A - Ambient Temperature (°C)

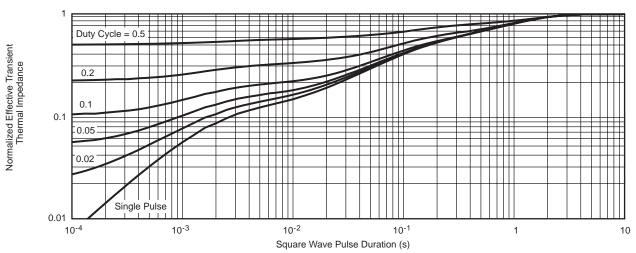
Power, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





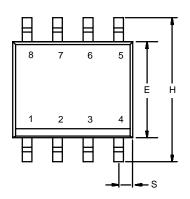
Normalized Thermal Transient Impedance, Junction-to-Ambient

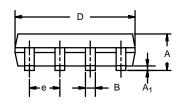


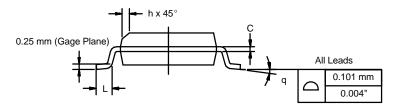
Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEADJEDEC Part Number: MS-012







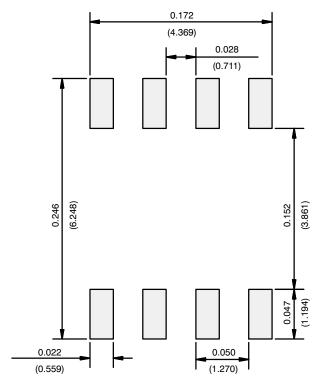
	MILLIMETERS		INC	INCHES		
DIM	Min	Max	Min	Max		
Α	1.35	1.75	0.053	0.069		
A ₁	0.10	0.20	0.004	0.008		
В	0.35	0.51	0.014	0.020		
С	0.19	0.25	0.0075	0.010		
D	4.80	5.00	0.189	0.196		
E	3.80	4.00	0.150	0.157		
е	1.27 BSC		0.050	BSC		
Н	5.80	6.20	0.228	0.244		
h	0.25	0.50	0.010	0.020		
L	0.50	0.93	0.020	0.037		
q	0°	8°	0°	8°		
S	0.44	0.64	0.018	0.026		
FCN: C-06527-Rev. I. 11-Sen-06						

ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)

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